Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
09/652,962	CHANG ET AL.
Examiner	Art Unit
Mark L. Shibuya	1639

SEARCHED				
Class	Subclass	Date	Examiner	
	Subciass	Date		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
435	6	8/22/2005	MS	
435	DIG 49	8/22/2005	MS	
525	50	8/22/2005	MS	
525/50,326.1, 330.3		8122105	mz	

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
WEST, Interference search, inventor search	8/22/2005	MS
STN, author, term search	8/22/2005	MS
PALM	8/22/2005	MS
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